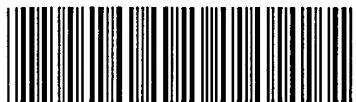


Search Notes

Application/Control No.

10/663,929

Examiner

Mark K. Han

Applicant(s)/Patent under
Reexamination

LAVI ET AL.

Art Unit

3767

SEARCHED

Class	Subclass	Date	Examiner
604	110 131	10/2/2006	Mak
	138 139		
	156 181		
	183 186		
	187 191		
	192 194		
	195 196		
	197 199		
	200 205		
	207 211		
	224 232		
	246 264		
	272 518		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text search	10/2/2006	Mak

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner